
Transmitters for use in industrial-process control systems - Part 2: Methods for inspection and routine testing

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EUROPEAN STANDARD

EN 60770-2

NORME EUROPÉENNE

EUROPÄISCHE NORM

April 2003

ICS 25.040.40; 17.020

English version

**Transmitters for use in industrial-process control systems
Part 2: Methods for inspection and routine testing
(IEC 60770-2:2003)**

Transmetteurs utilisés dans les systèmes
de conduite des processus industriels
Partie 2: Méthodes pour l'inspection
et les essais individuels de série
(CEI 60770-2:2003)

Messumformer für industrielle
Prozessleittechnik
Teil 2: Verfahren für Abnahme
und Stückprüfung
(IEC 60770-2:2003)

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This European Standard was approved by CENELEC on 2003-04-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 65B/468/FDIS, future edition 2 of IEC 60770-2, prepared by SC 65B, Devices, of IEC TC 65, Industrial-process measurement and control, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60770-2 on 2003-04-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2004-01-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2006-04-01

Annexes designated "normative" are part of the body of the standard.
In this standard, annex ZA is normative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60770-2:2003 was approved by CENELEC as a European Standard without any modification.

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-351	1998	International Electrotechnical Vocabulary Part 351: Automatic control	-	-
IEC 60381-1	1982	Analogue signals for process control systems Part 1: Direct current signals	HD 452.1 S1	1984
IEC 60382	1991	Analogue pneumatic signal for process control systems	EN 60382	1993
IEC 60410	1973	Sampling plans and procedures for inspection by attributes	-	-
IEC 60770-1	1999	Transmitters for use in industrial-process control systems Part 1: Methods for performance evaluation	EN 60770-1	1999
IEC 61298-1	1995	Process measurement and control devices - General methods and procedures for evaluating performance Part 1: General considerations	EN 61298-1	1995
IEC 61298-2	1995	Part 2: Tests under reference conditions	EN 61298-2	1995
IEC 61298-3	1998	Part 3: Tests for the effects of influence quantities	EN 61298-3	1998
IEC 61298-4	1995	Part 4: Evaluation report content	EN 61298-4	1995
IEC 62098	2000	Evaluation methods for microprocessor-based instruments	-	-

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INTERNATIONAL STANDARD

IEC 60770-2

Second edition
2003-01

Transmitters for use in industrial-process control systems –

Part 2: Methods for inspection and routine testing

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*Transmetteurs utilisés dans les systèmes de conduite
des processus industriels –*

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Partie 2:

Méthodes pour l'inspection et les essais individuels de série

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Commission Electrotechnique Internationale
International Electrotechnical Commission
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**TRANSMITTERS FOR USE IN INDUSTRIAL-PROCESS
CONTROL SYSTEMS –**
Part 2: Methods for inspection and routine testing

FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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- 3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.
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- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60770-2 has been prepared by subcommittee 65B: Devices, of IEC technical committee 65: Industrial-process measurement and control.

This second edition cancels and replaces the first edition published in 1989 and constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
65B/468/FDIS	65B/477/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A bilingual edition may be issued at a later date.

The committee has decided that the contents of this publication will remain unchanged until 2008. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.